SCANNING PROBE MICROSCOPE (SPM)

Brand-Model

SPA300HV, SII NanoTechnology Inc.

Descriptions

SPM allows the process of monitoring sample topography, scanning area, the cantilever, and the scanner to determine the best operating conditions. As the measurement parameters are optimized, the cantilever's vibration amplitude and operation frequency are automatically adjusted based on the sample and cantilever type.

Service Offer: Measurement of the surface topography as well as a wide variety of material properties at nanometer scale in different mode such as STM (Scanning Tunnel Microscope), AFM (Atomic Force Microscope), DFM (Dynamic Force Mode/Microscope), KFM (Kelvin Probe Force Microscope) and more.

Type of samples: Polymers, ceramics, composites, glass, and biological samples.

Specifications

Probe station controller: Z Axis Servo Controller

Displacement Signal: Displacement of band signal (for AFM), displacement of amplitude signal (for DFM) and changes in the tunnel current (for STM)

Temperature control: heating to 800°C (max)

Scanner: XY Raster Scanner, 3-D image can be generated using the Z data corresponding to the XY coordinate data

Service location
C21-207 *Scanning Probe Microscope Laboratory*
Block: C21

Further Information

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